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BUK9E2R8-60E

N-channel TrenchMOS logic level FET

11 September 2012

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel MOSFET in a SOT226 package using TrenchMOS technology. This product has been designed and qualified to AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Repetitive avalanche rated
- Suitable for thermally demanding environments due to 175 °C rating
- True logic level gate with VGS(th) rating of greater than 0.5V at 175 °C

1.3 Applications

- 12 V Automotive systems
- Motors, lamps and solenoid control
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25^\circ\text{C}$; $T_j \leq 175^\circ\text{C}$		-	-	60	V
I_D	drain current	$V_{GS} = 5\text{ V}$; $T_{mb} = 25^\circ\text{C}$; Fig. 1	[1]	-	-	120	A
P_{tot}	total power dissipation	$T_{mb} = 25^\circ\text{C}$; Fig. 2		-	-	349	W
Static characteristics							
R_{DSon}	drain-source on-state resistance	$V_{GS} = 5\text{ V}$; $I_D = 25\text{ A}$; $T_j = 25^\circ\text{C}$; Fig. 11		-	2.2	2.8	$\text{m}\Omega$
Dynamic characteristics							
Q_{GD}	gate-drain charge	$V_{GS} = 5\text{ V}$; $I_D = 25\text{ A}$; $V_{DS} = 48\text{ V}$; Fig. 13 ; Fig. 14		-	41.2	-	nC

[1] Continuous current is limited by package.



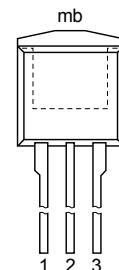
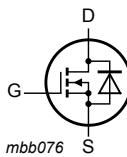
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2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	 I2PAK (SOT226)	
2	D	drain		
3	S	source		
mb	D	mounting base; connected to drain		

3. Ordering information

Table 3. Ordering information

Type number	Package			Version
	Name	Description	Version	
BUK9E2R8-60E	I2PAK	plastic single-ended package (I2PAK); TO-262		SOT226

4. Marking

Table 4. Marking codes

Type number	Marking code
BUK9E2R8-60E	BUK9E2R8-60E

5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25^\circ\text{C}$; $T_j \leq 175^\circ\text{C}$		-	60	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20\text{ k}\Omega$		-	60	V
V_{GS}	gate-source voltage	$T_j \leq 175^\circ\text{C}$; DC		-10	10	V
		$T_j \leq 175^\circ\text{C}$; Pulsed	[1][2]	-15	15	V
I_D	drain current	$T_{mb} = 25^\circ\text{C}$; $V_{GS} = 5\text{ V}$; Fig. 1	[3]	-	120	A
		$T_{mb} = 100^\circ\text{C}$; $V_{GS} = 5\text{ V}$; Fig. 1	[3]	-	120	A
I_{DM}	peak drain current	$T_{mb} = 25^\circ\text{C}$; pulsed; $t_p \leq 10\text{ }\mu\text{s}$; Fig. 4		-	952	A
P_{tot}	total power dissipation	$T_{mb} = 25^\circ\text{C}$; Fig. 2		-	349	W

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Symbol	Parameter	Conditions		Min	Max	Unit
T_{stg}	storage temperature			-55	175	°C
T_j	junction temperature			-55	175	°C
Source-drain diode						
I_S	source current	$T_{mb} = 25 \text{ }^\circ\text{C}$	[3]	-	120	A
I_{SM}	peak source current	pulsed; $t_p \leq 10 \mu\text{s}$; $T_{mb} = 25 \text{ }^\circ\text{C}$		-	952	A
Avalanche ruggedness						
$E_{DS(AL)s}$	non-repetitive drain-source avalanche energy	$I_D = 120 \text{ A}$; $V_{sup} \leq 60 \text{ V}$; $R_{GS} = 50 \Omega$; $V_{GS} = 5 \text{ V}$; $T_{j(init)} = 25 \text{ }^\circ\text{C}$; unclamped; Fig. 3	[4][5]	-	655	mJ

- [1] Accumulated pulse duration up to 50 hours delivers zero defect ppm
- [2] Significantly longer life times are achieved by lowering T_j and or V_{GS}
- [3] Continuous current is limited by package.
- [4] Single-pulse avalanche rating limited by maximum junction temperature of $175 \text{ }^\circ\text{C}$.
- [5] Refer to application note AN10273 for further information.

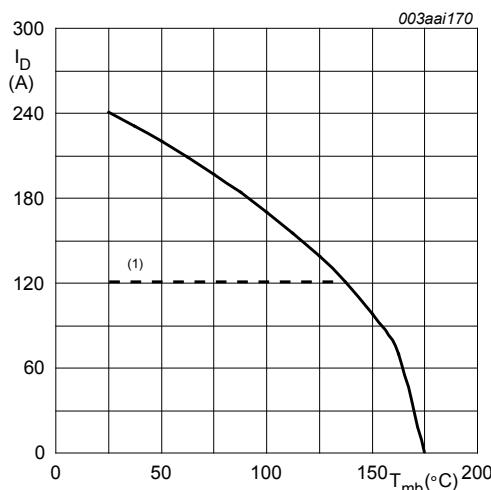


Fig. 1. Continuous drain current as a function of mounting base temperature

$V_{GS} \geq 5 \text{ V}$

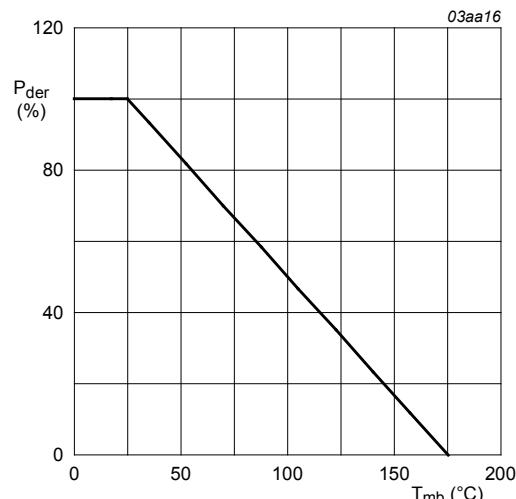


Fig. 2. Normalized total power dissipation as a function of mounting base temperature

$$P_{der} = \frac{P_{tot}}{P_{tot}(25^\circ\text{C})} \times 100 \%$$

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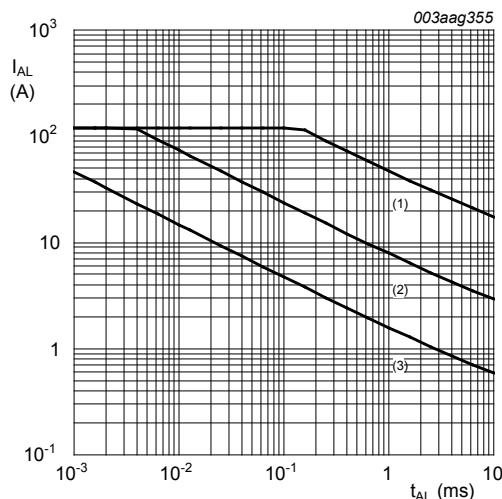


Fig. 3. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time

(1) $T_j (init) = 25^\circ C$; (2) $T_j (init) = 150^\circ C$; (3) Repetitive Avalanche

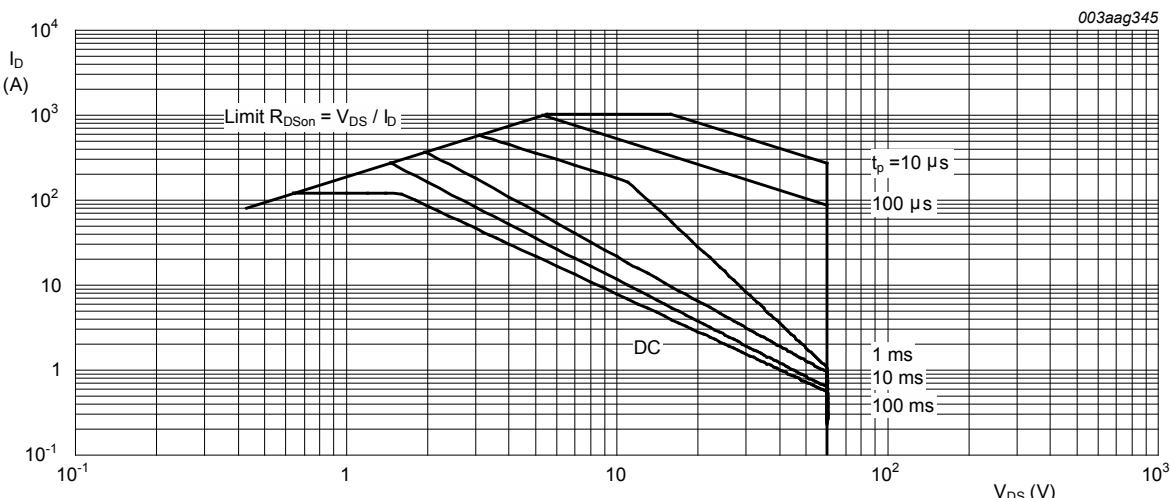


Fig. 4. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

$T_{mb} = 25^\circ C$; I_{DM} is a single pulse

6. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	Fig. 5		-	-	0.43	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	vertical in still air		-	65	-	K/W

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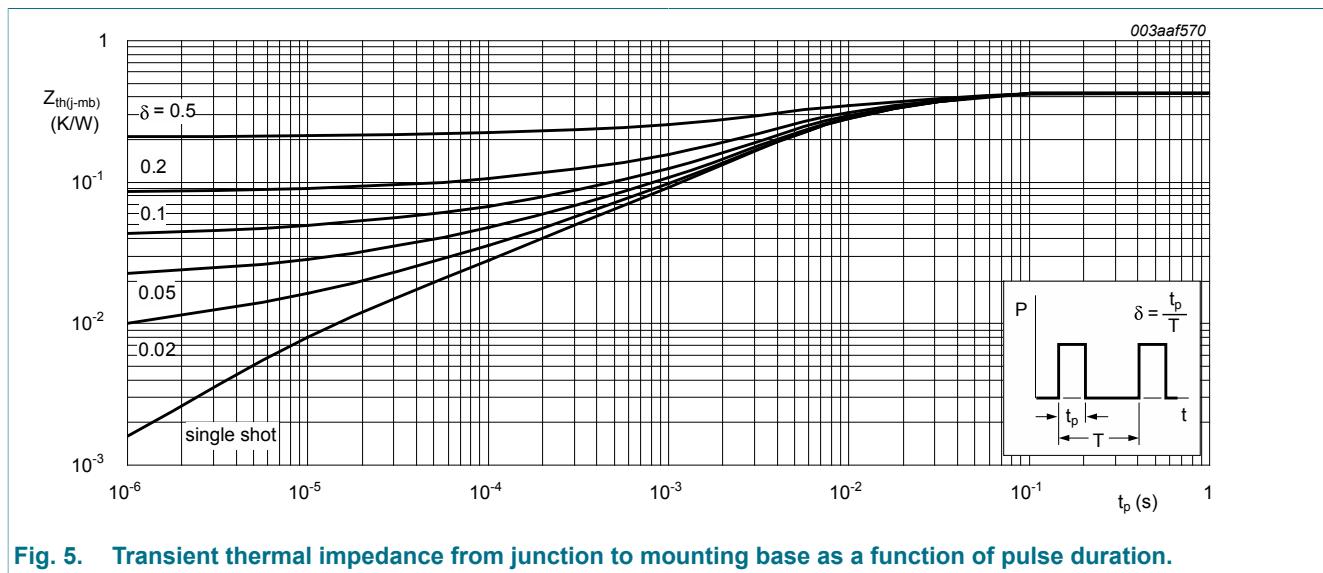


Fig. 5. Transient thermal impedance from junction to mounting base as a function of pulse duration.

7. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Static characteristics							
V _{(BR)DSS}	drain-source breakdown voltage	I _D = 250 μ A; V _{GS} = 0 V; T _j = 25 °C		60	-	-	V
		I _D = 250 μ A; V _{GS} = 0 V; T _j = -55 °C		54	-	-	V
Dynamic characteristics							
V _{GS(th)}	gate-source threshold voltage	I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 25 °C; Fig. 9 ; Fig. 10		1.4	1.7	2.1	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = -55 °C; Fig. 9		-	-	2.45	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 175 °C; Fig. 9		0.5	-	-	V
I _{DSS}	drain leakage current	V _{DS} = 60 V; V _{GS} = 0 V; T _j = 25 °C		-	0.08	1	μ A
		V _{DS} = 60 V; V _{GS} = 0 V; T _j = 175 °C		-	-	500	μ A
I _{GSS}	gate leakage current	V _{GS} = 10 V; V _{DS} = 0 V; T _j = 25 °C		-	2	100	nA
		V _{GS} = -10 V; V _{DS} = 0 V; T _j = 25 °C		-	2	100	nA
R _{DSon}	drain-source on-state resistance	V _{GS} = 5 V; I _D = 25 A; T _j = 25 °C; Fig. 11		-	2.2	2.8	m Ω
		V _{GS} = 10 V; I _D = 25 A; T _j = 25 °C; Fig. 11		-	2	2.6	m Ω
		V _{GS} = 5 V; I _D = 25 A; T _j = 175 °C; Fig. 12 ; Fig. 11		-	-	6.2	m Ω
Dynamic characteristics							
Q _{G(tot)}	total gate charge	I _D = 25 A; V _{DS} = 48 V; V _{GS} = 5 V; Fig. 13 ; Fig. 14		-	120	-	nC
Q _{GS}	gate-source charge			-	25.6	-	nC

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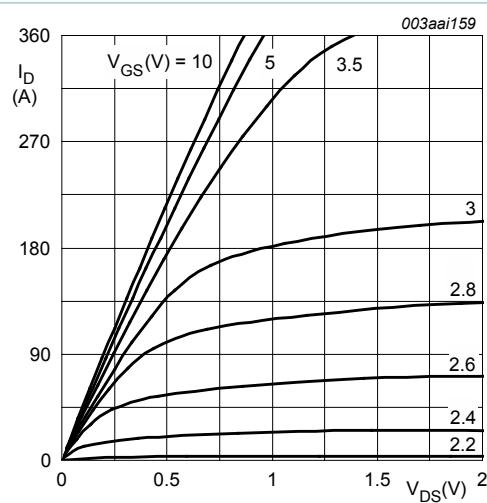
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Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Q_{GD}	gate-drain charge			-	41.2	-	nC
C_{iss}	input capacitance	$V_{GS} = 0 \text{ V}$; $V_{DS} = 25 \text{ V}$; $f = 1 \text{ MHz}$;		-	13070	17450	pF
C_{oss}	output capacitance	$T_j = 25 \text{ }^\circ\text{C}$; Fig. 15		-	1051	1260	pF
C_{rss}	reverse transfer capacitance			-	558	770	pF
$t_{d(on)}$	turn-on delay time	$V_{DS} = 25 \text{ V}$; $R_L = 1.8 \Omega$; $V_{GS} = 5 \text{ V}$;		-	71	-	ns
t_r	rise time	$R_{G(ext)} = 5 \Omega$		-	119	-	ns
$t_{d(off)}$	turn-off delay time			-	224	-	ns
t_f	fall time			-	128	-	ns
L_D	internal drain inductance	from upper edge of drain mounting base to center of die		-	2.5	-	nH
		from drain lead 6mm from package to centre of die		-	4.5	-	nH
L_S	internal source inductance	from source lead to source bonding pad		-	7.5	-	nH

Source-drain diode

V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ }^\circ\text{C}$; Fig. 16		-	0.77	1.2	V
t_{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A}/\mu\text{s}$; $V_{GS} = 0 \text{ V}$;		-	53	-	ns
Q_r	recovered charge	$V_{DS} = 25 \text{ V}$		-	98	-	nC



$T_j = 25 \text{ }^\circ\text{C}$; $t_p = 300 \mu\text{s}$

Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values

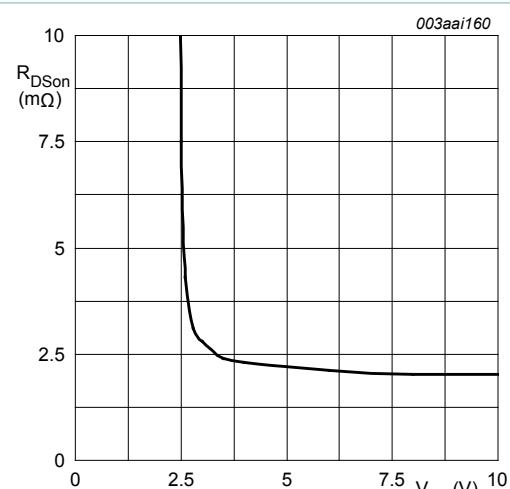


Fig. 7. Drain-source on-state resistance as a function of gate-source voltage; typical values

$T_j = 25 \text{ }^\circ\text{C}$; $I_D = 25 \text{ A}$

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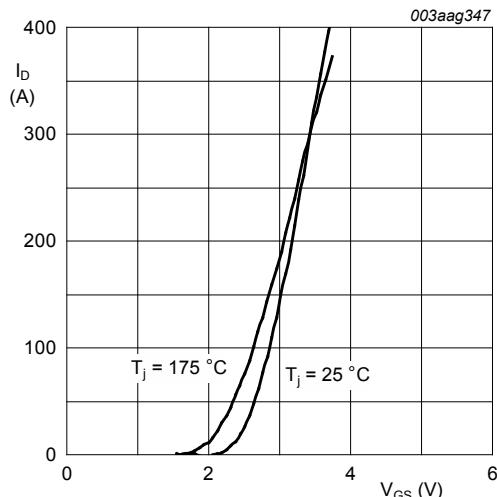


Fig. 8. Transfer characteristics: drain current as a function of gate-source voltage; typical values

$V_{DS} = 12\text{ V}$

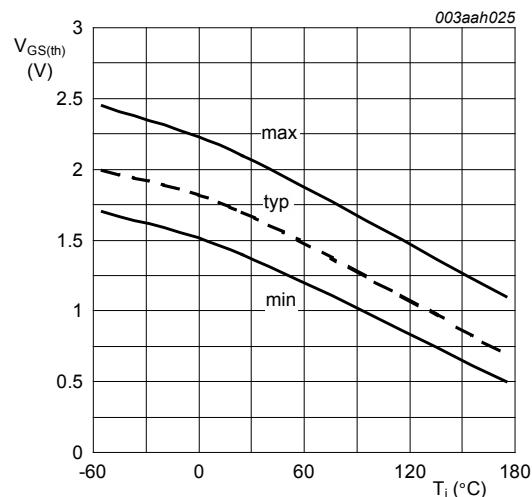


Fig. 9. Gate-source threshold voltage as a function of junction temperature

$I_D = 1\text{ mA}; V_{DS} = V_{GS}$

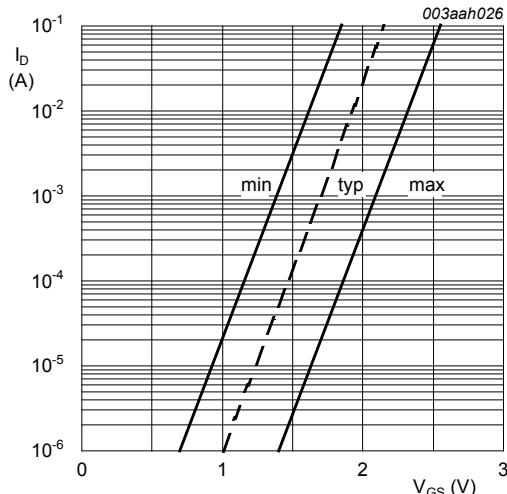
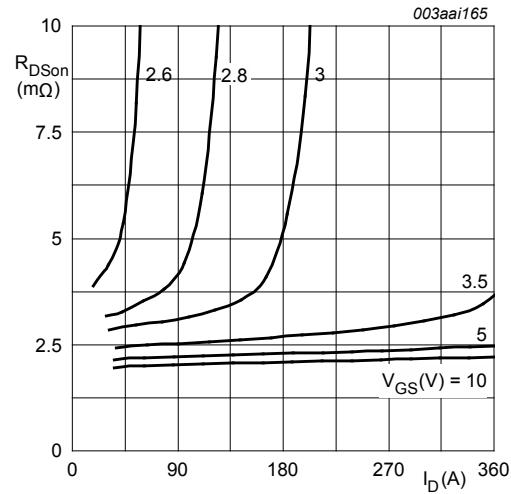


Fig. 10. Sub-threshold drain current as a function of gate-source voltage

$T_j = 25\text{ °C}; V_{DS} = 5\text{ V}$



$T_j = 25\text{ °C}; t_p = 300\text{ }\mu\text{s}$

Fig. 11. Drain-source on-state resistance as a function of drain current; typical values

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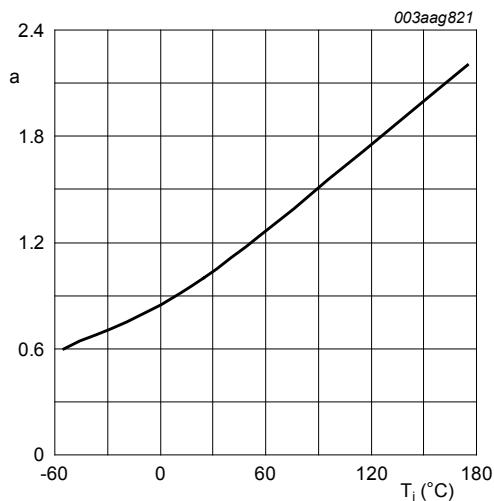
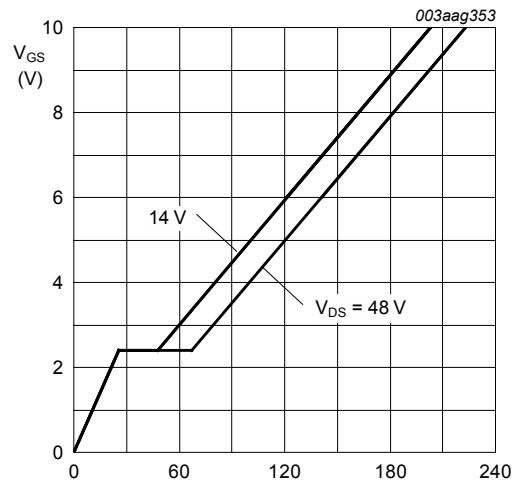


Fig. 12. Normalized drain-source on-state resistance factor as a function of junction temperature

$$a = \frac{R_{DSon}}{R_{DSon}(25\text{ }^{\circ}\text{C})}$$



$T_j = 25\text{ }^{\circ}\text{C}$; $I_D = 25\text{ A}$

Fig. 14. Gate-source voltage as a function of gate charge; typical values

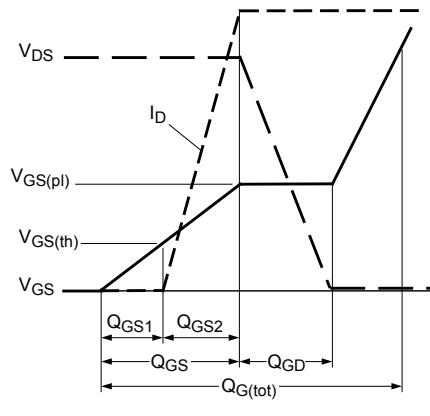
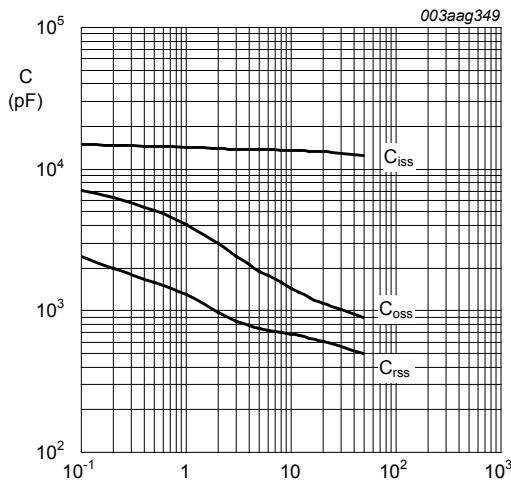
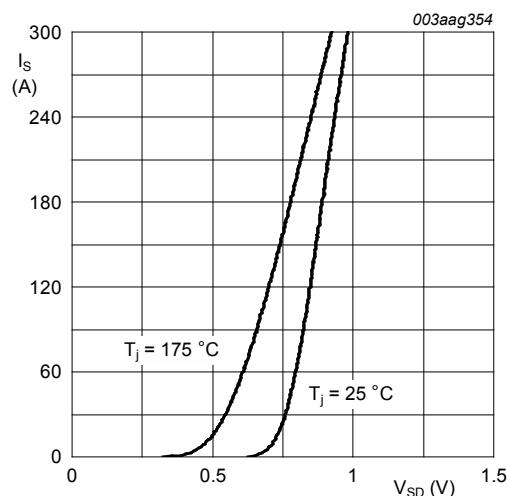


Fig. 13. Gate charge waveform definitions



$V_{GS} = 0\text{ V}$; $f = 1\text{ MHz}$

Fig. 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

NXP Semiconductors**BUK9E2R8-60E****N-channel TrenchMOS logic level FET** $V_{GS} = 0 \text{ V}$ **Fig. 16. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values**

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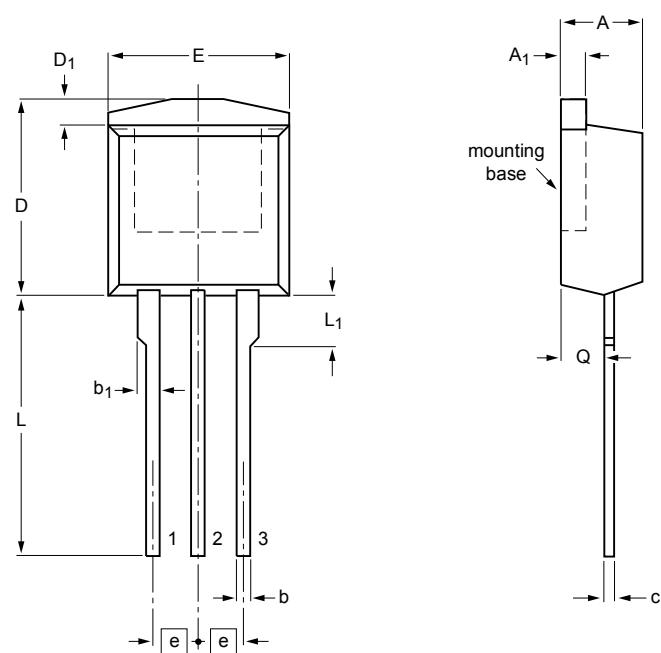
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8. Package outline

Plastic single-ended package (I2PAK); low-profile 3-lead TO-262

SOT226



0 5 10 mm
scale

DIMENSIONS (mm are the original dimensions)

UNIT	A	A ₁	b	b ₁	c	D _{max}	D ₁	E	e	L	L ₁	Q
mm	4.5 4.1	1.40 1.27	0.85 0.60	1.3 1.0	0.7 0.4	11	1.6 1.2	10.3 9.7	2.54	15.0 13.5	3.30 2.79	2.6 2.2

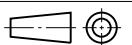
OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT226		TO-262				06-02-14 09-08-25

Fig. 17. Package outline I2PAK (SOT226)

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9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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